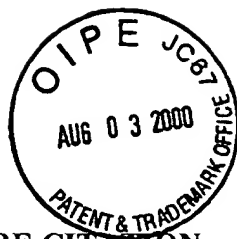


FORM PTO-1449

## INFORMATION DISCLOSURE CITATION



Sheet 1 of 1  
 Docket No.: Bao 16-25-12  
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 Applicants: Bao et al.  
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EXAMINER INITIALS *	DOCUMENT NUMBER	DATE	NAME	CLASS	SUB-CLASS	FILING DATE
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gzc	B	5,773,197	06/30/1998	Carter et al.		
gzc	C	5,895,263	04/20/1999	Carter et al.		
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\*EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP 609; draw line through citation if in conformance and not considered. Include copy of this form with next communication to applicant.

gzc Eichen

12/31/01